

Cantilever Technology Parametric probe cards



S600 ULTRA LOW LEAKAGE PROBE CARDS DATA SHEET

Synergie CAD PSC is approved by KEITHLEY to manufacture S600 Ultra Low Leakage probe cards, including Blade and Coaxial Epoxy technology.

Ultra Low Leakage probe card manufactured and maintained by Synergie CAD Group, is the best way to enable all the capabilities of the tester by assuming an ideal interface between the wafer and the tester.



With the reduction of processed nodes, with the increase of the number of layers processed on the wafer and with the apparition of the copper on wafers, parametric tests is now a key point in the total test strategy.



Today the need is to measure very small residue of etching process, so low leakage capability is very important.

But the lower leakage has to be measured, the longer is the time. The probe card doesn't have to increase this time, that's why Grenoble Team develops and makes continuous improvement of its low leakage manufacturing process to offer, either, new capability and better performance.

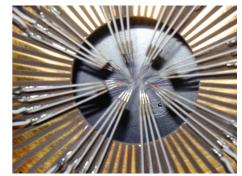
As example, Synergie CAD manufactures its own specific strip line ceramic blades and coaxial epoxy needles to quarantee our specifications.

Synergie CAD is proud to announce that as a result of it efforts to develop new technologies, KEITHLEY give to the company the agreement to manufacture Ultra Low Leakage probe cards

for S600 testers in all cantilever technologies available for the parametric test: Ceramic Strip Line Blades (since 2000), Coaxial Epoxy (since 2002).

As Synergie CAD is constantly listening to the needs of his customers, the high voltage application is now available to test automotive applications.

Synergie CAD also shares its experience and its know-how to manufacture parametric probe cards for other testers as Agilent, Suss Microtech, ReedHlom...



Web site: www.synergie-cad.fr www.synergie-cad-probe.fr

Your Contacts: <u>jl.bosser@synergie-cad.fr</u> Or

info@synergie-cad-probe.fr





SPECIFICATIONS	VALUES
Probe Card	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
Typical Probe Card Depth (from Bottom)	120-160 mils +/- 5
Minimum Pitch	80 µm
Minimum Pad dimensions	50 μm
Tip position	in line
Number of probes	1-64
Probe position alignment accuracy	+/- 5 μm
Operating temperature	-40 ℃ to 200 ℃
Rotational specification	+/- 1 °
Typical Overdrive	3 mils
Typical touchdown	250 000 to 1 000 000
Needles	
Type	Strip line Ceramic Blades
Туре	Coaxial Epoxy needles
Material	Copper Beryllium or Tungsten
	Rhenium
Tip diameter	1 to 2 mils (25 to 50 μm)
Tip length	7 to 25 mils (175 to 625 μm)
Planarity	+/- 5 μm
Pad specification	
Material	Aluminum, Copper, Polysilicon, other
Flatness between 2 pads	+/- 10 μm
Probe mark dimensions	30 to 60 μm
Electrical Specifications	
Leakage : Pin to Ground , Pin to Pin	
60238 - Low Leakage probe cards	0.2 pA/V
60239 - Ultra Low Leakage Blade probe cards	1 fA/V
60237 - Ultra Low Leakage Coax-Epoxy probe cards	1 fA/V
Maximum current per pin (depending on material	Depending on needle
tested)	dimension and material from
,	300 mA to 1.5 A
High Voltage application	1000 V
Typical parasitic capacitance	NA NA
Typical DC contact resistance (Probe)	0.5 to 1 Ohm
Maximum DC contact resistance (Tip to Test equipment)	2 Ohms +/- 1
PCB specification	
Material	Polyimide, Pcb Kit provided and guaranteed by Keithley
Thickness	j
60237-60239	Double deck probe cards
60238	3.2 mm with gold pins plugs
Components pre-mounted	ID EEprom

Ask for our special Order form to give us all data necessary for manufacturing.

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